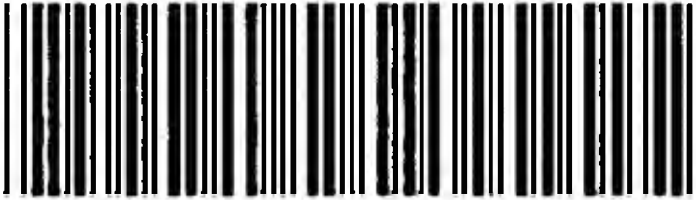


<div>Search Notes</div> <div></div>	Application No.	Applicant(s)	
	10/604,244	TAI ET AL.	
	Examiner	Art Unit	
	Toan M Le	2863	

SEARCHED			
Class	Subclass	Date	Examiner
702	84	8/31/2004	TL
700	109	8/31/2004	TL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Wafer In-line Yield Prediction	9/1/2004	TL
Wafer Yield Analysis; Statistical; Regression; Sample	9/1/2004	TL
Wafer Quality Control Analysis; Parameter; Lot; Sample	8/31/2004	TL
Quality Control, Sample, Parameter, Search, Database, Analyzing, Correlating, Wafer	8/31/2004	TL